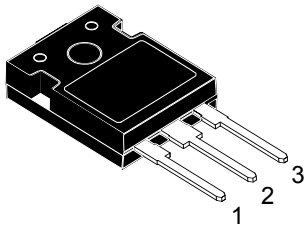
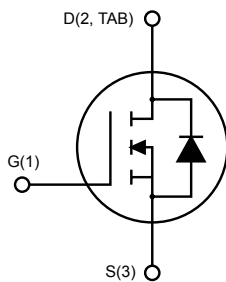



Automotive-grade silicon carbide Power MOSFET 1200 V, 12 A, 520 mΩ (typ., $T_J = 150\text{ °C}$) in an HiP247™ package


HiP247™


AM01475v1_noZen



Features

- AEC-Q101 qualified 
- Very tight variation of on-resistance vs. temperature
- Very high operating temperature capability ($T_J = 200\text{ °C}$)
- Very fast and robust intrinsic body diode
- Low capacitance

Applications

- Motor drives
- EV chargers
- High voltage DC-DC converters
- Switch mode power supplies

Description

This silicon carbide Power MOSFET is produced exploiting the advanced, innovative properties of wide bandgap materials. This results in unsurpassed on-resistance per unit area and very good switching performance almost independent of temperature. The outstanding thermal properties of the SiC material, combined with the device's housing in the proprietary HiP247™ package, allows designers to use an industry-standard outline with significantly improved thermal capability. These features render the device perfectly suitable for high-efficiency and high power density applications.

Product status link

[SCT10N120AG](#)

Product summary

Order code	SCT10N120AG
Marking	SCT10N120AG
Package	HiP247™
Packing	Tube

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{DS}	Drain-source voltage	1200	V
V_{GS}	Gate-source voltage	-10 to 25	V
I_D	Drain current (continuous) at $T_C = 25\text{ °C}$	12	A
I_D	Drain current (continuous) at $T_C = 100\text{ °C}$	10	A
$I_{DM}^{(1)}$	Drain current (pulsed)	24	A
P_{TOT}	Total power dissipation at $T_C = 25\text{ °C}$	150	W
T_{stg}	Storage temperature range	-55 to 200	°C
T_j	Operating junction temperature range		°C

1. Pulse width limited by safe operating area.

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	1.17	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient	40	°C/W

2 Electrical characteristics

($T_{CASE} = 25\text{ °C}$ unless otherwise specified).

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0\text{ V}, I_D = 1\text{ mA}$	1200			V
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 1200\text{ V}, V_{GS} = 0\text{ V}$			10	μA
		$V_{DS} = 1200\text{ V}, V_{GS} = 0\text{ V}, T_J = 200\text{ °C}$ ⁽¹⁾			100	μA
I_{GSS}	Gate-body leakage current	$V_{DS} = 0\text{ V}, V_{GS} = -10\text{ to }25\text{ V}$			100	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	1.8	3.5		V
$R_{DS(on)}$	Static drain-source on-resistance	$V_{GS} = 20\text{ V}, I_D = 6\text{ A}$		500	690	m Ω
		$V_{GS} = 20\text{ V}, I_D = 6\text{ A},$ $T_J = 150\text{ °C}$		520		m Ω
		$V_{GS} = 20\text{ V}, I_D = 6\text{ A},$ $T_J = 200\text{ °C}$		580		m Ω

1. Defined by design, not subject to production test.

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	$V_{DS} = 400\text{ V}, f = 1\text{ MHz},$ $V_{GS} = 0\text{ V}$	-	290	-	pF
C_{oss}	Output capacitance		-	30	-	pF
C_{rSS}	Reverse transfer capacitance		-	9	-	pF
Q_g	Total gate charge	$V_{DD} = 800\text{ V}, I_D = 6\text{ A},$ $V_{GS} = 0\text{ to }20\text{ V}$	-	22	-	nC
Q_{gs}	Gate-source charge		-	3	-	nC
Q_{gd}	Gate-drain charge		-	10	-	nC
R_g	Gate input resistance		$f=1\text{ MHz}, I_D=0\text{ A}$	-	8	-

Table 5. Switching energy (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
E_{on}	Turn-on switching energy	$V_{DD} = 800\text{ V}, I_D = 6\text{ A}$ $R_G = 10\text{ }\Omega, V_{GS} = -5\text{ to }20\text{ V}$	-	90	-	μJ
E_{off}	Turn-off switching energy		-	30	-	μJ
E_{on}	Turn-on switching energy	$V_{DD} = 800\text{ V}, I_D = 6\text{ A}$ $R_G = 10\text{ }\Omega, V_{GS} = -5\text{ to }20\text{ V}$ $T_J = 150\text{ °C}$	-	104	-	μJ
E_{off}	Turn-off switching energy		-	33	-	μJ

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 800\text{ V}$, $I_D = 6\text{ A}$, $R_G = 10\ \Omega$, $V_{GS} = -5\text{ to }20\text{ V}$	-	7	-	ns
t_f	Fall time		-	17	-	ns
$t_{d(off)}$	Turn-off delay time		-	14	-	ns
t_r	Rise time		-	12	-	ns

Table 7. Reverse SiC diode characteristics

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
V_{SD}	Diode forward voltage	$I_F = 6\text{ A}$, $V_{GS} = 0\text{ V}$	-	4.3	-	V
t_{rr}	Reverse recovery time	$I_{SD} = 6\text{ A}$, $di/dt = 2000\text{ A}/\mu\text{s}$ $V_{DD} = 800\text{ V}$, $T_J = 150\text{ }^\circ\text{C}$	-	16	-	ns
Q_{rr}	Reverse recovery charge		-	107	-	nC
I_{RRM}	Reverse recovery current		-	12	-	A

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

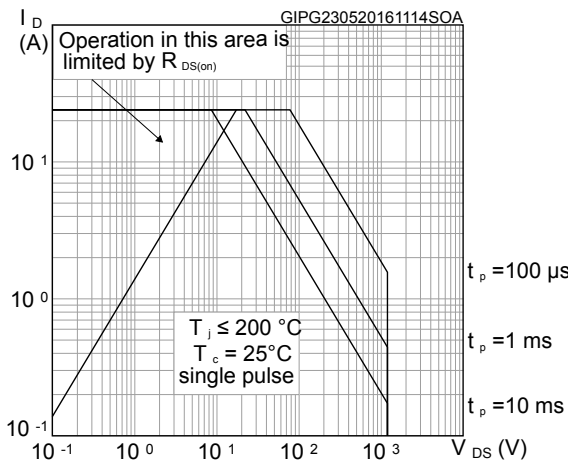


Figure 2. Thermal impedance

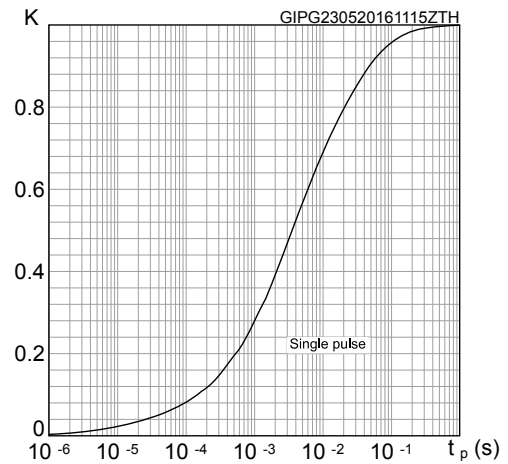


Figure 3. Output characteristics ($T_J = 25\text{ °C}$)

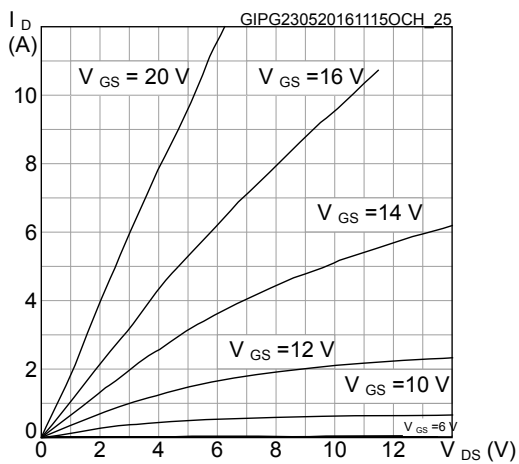


Figure 4. Output characteristics ($T_J = 150\text{ °C}$)

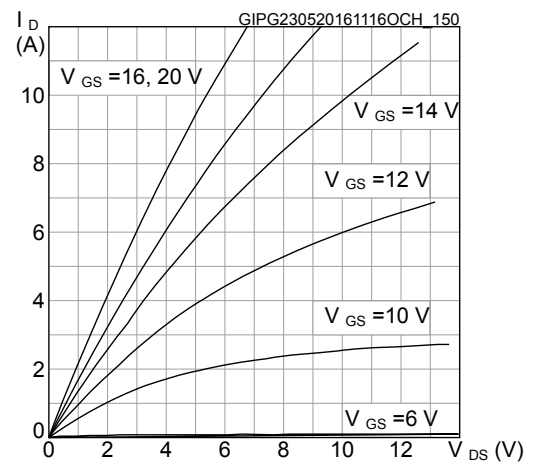


Figure 5. Output characteristics ($T_J = 200\text{ }^\circ\text{C}$)

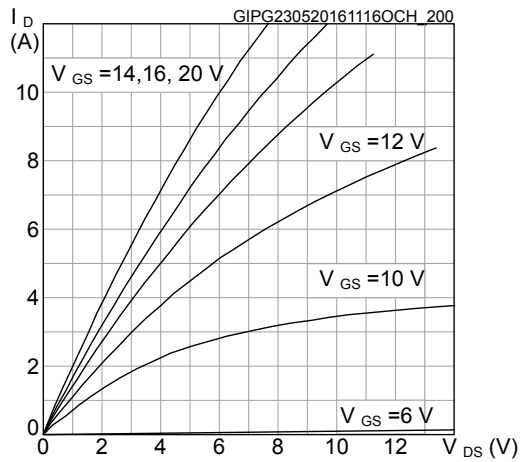


Figure 6. Transfer characteristics

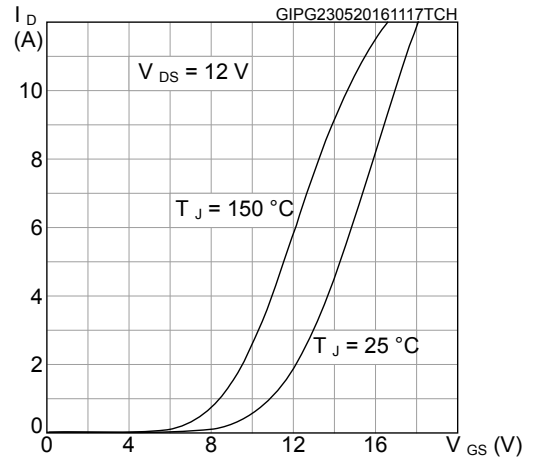


Figure 7. Power dissipation

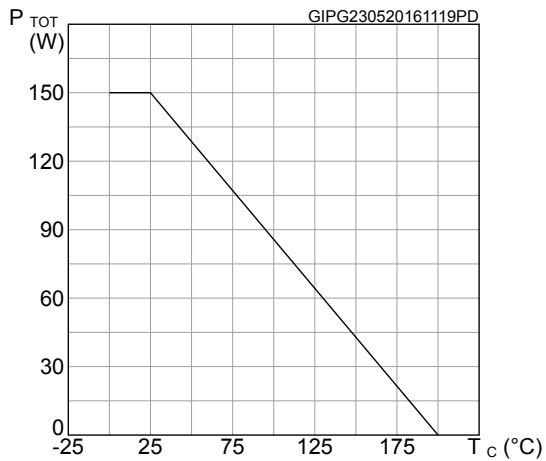


Figure 8. Gate charge vs gate-source voltage

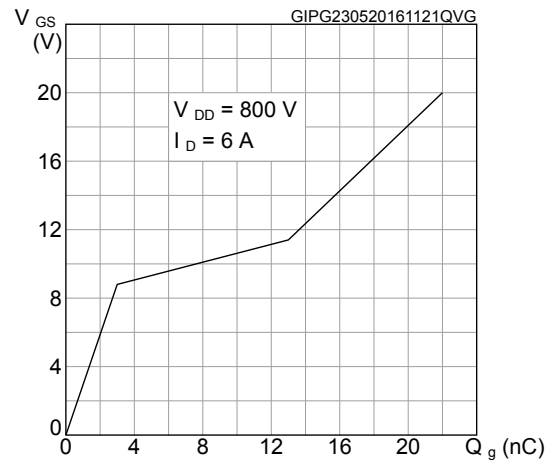


Figure 9. Capacitance variations

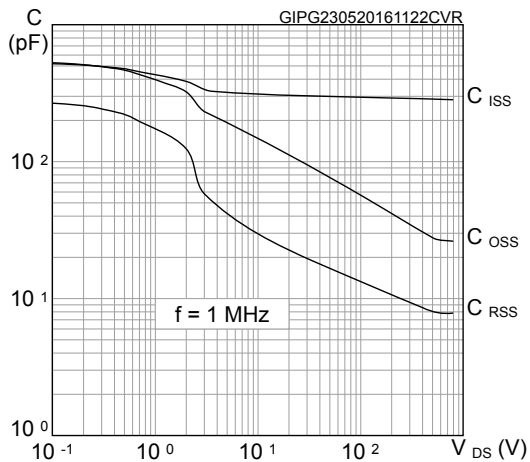


Figure 10. Switching energy vs. drain current

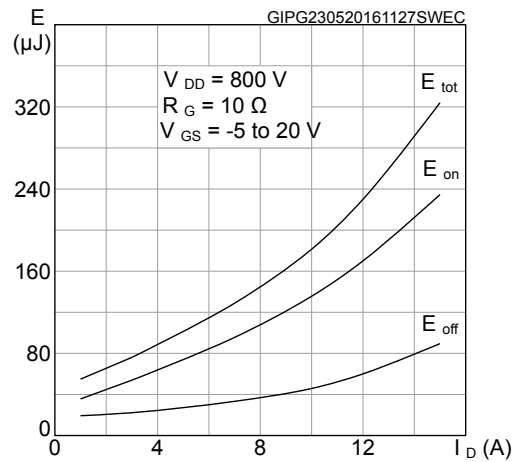


Figure 11. Switching energy vs. junction temperature

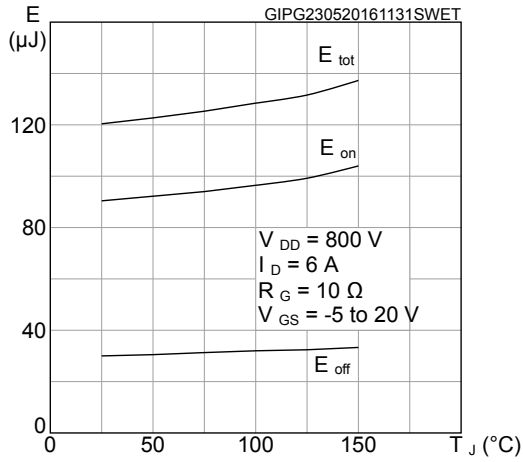


Figure 12. Normalized $V_{(BR)DSS}$ vs. temperature

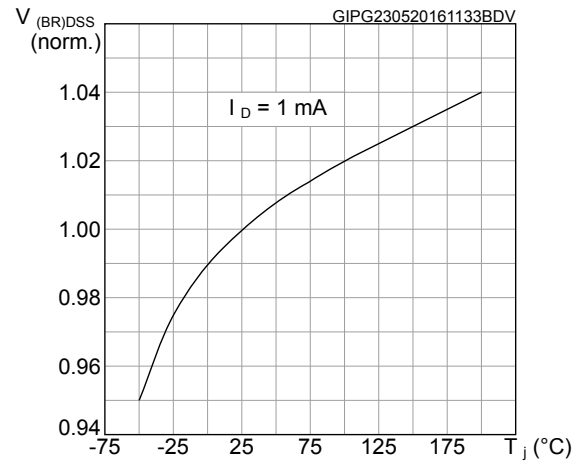


Figure 13. Normalized gate threshold voltage vs. temperature

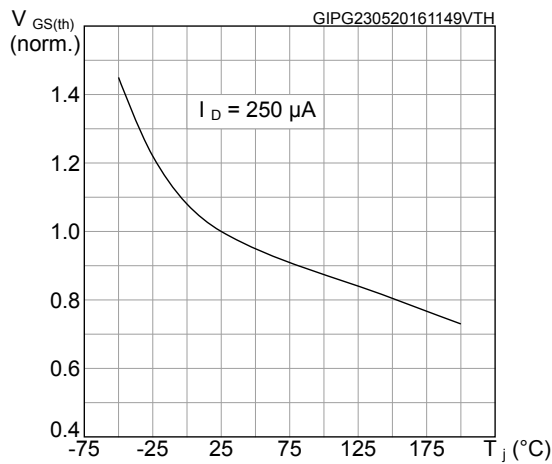


Figure 14. Normalized on-resistance vs. temperature

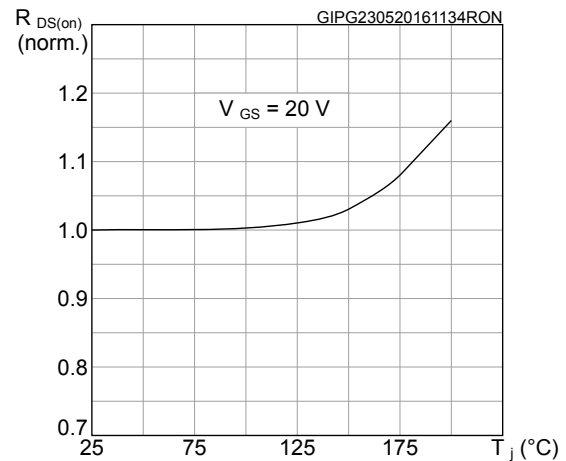


Figure 15. Body diode characteristics ($T_J = -50\text{ }^\circ\text{C}$)

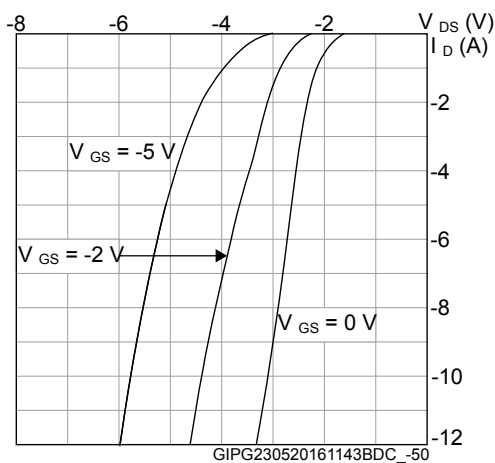


Figure 16. Body diode characteristics ($T_J = 25\text{ }^\circ\text{C}$)

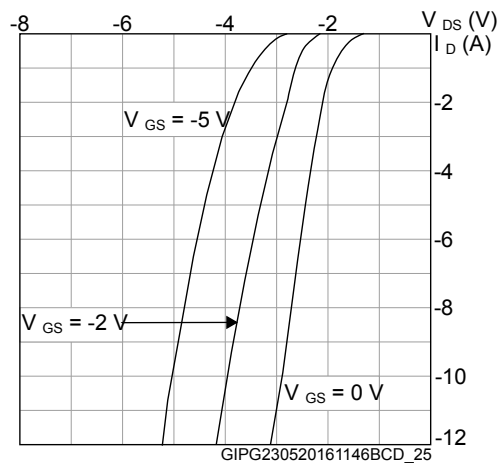


Figure 17. Body diode characteristics ($T_J = 150\text{ }^\circ\text{C}$)

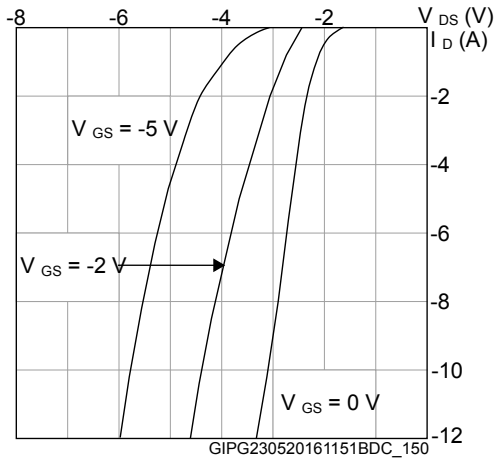


Figure 18. 3rd quadrant characteristics ($T_J = -50\text{ }^\circ\text{C}$)

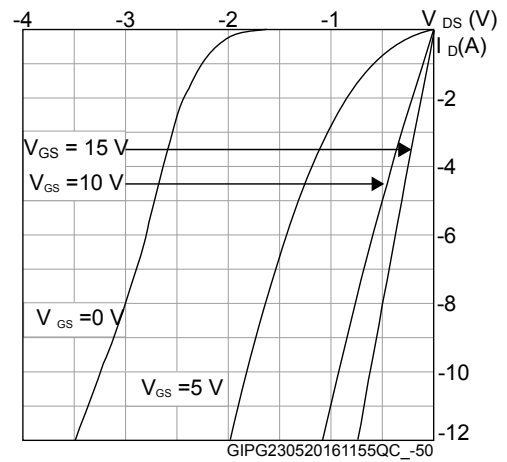


Figure 19. 3rd quadrant characteristics ($T_J = 25\text{ }^\circ\text{C}$)

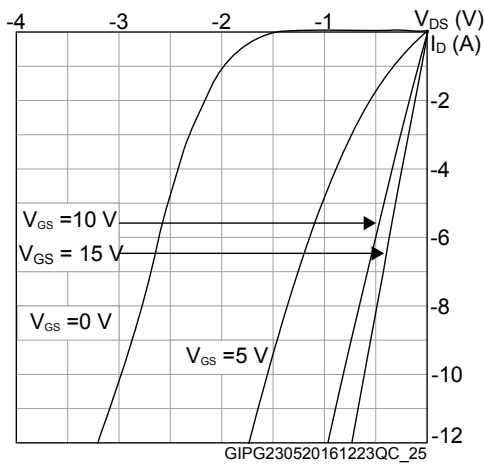
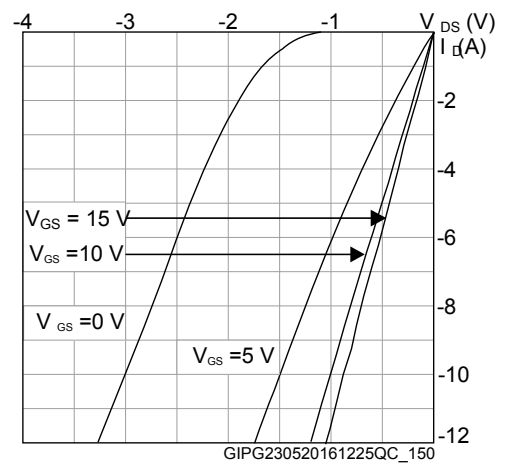
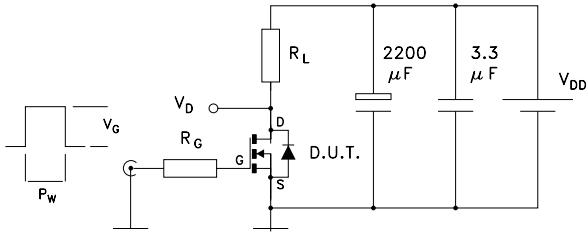


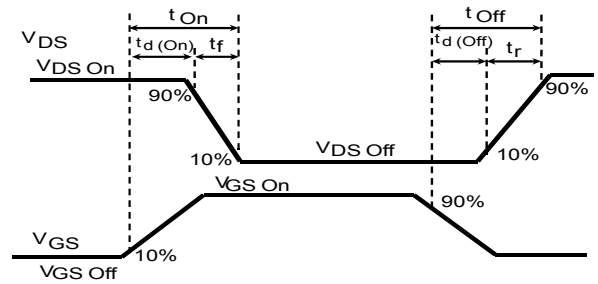
Figure 20. 3rd quadrant characteristics ($T_J = 150\text{ }^\circ\text{C}$)



3 Test circuits

Figure 21. Switching test waveforms for transition times


GIPD101020141511FSR

Figure 22. Clamped inductive switching waveform


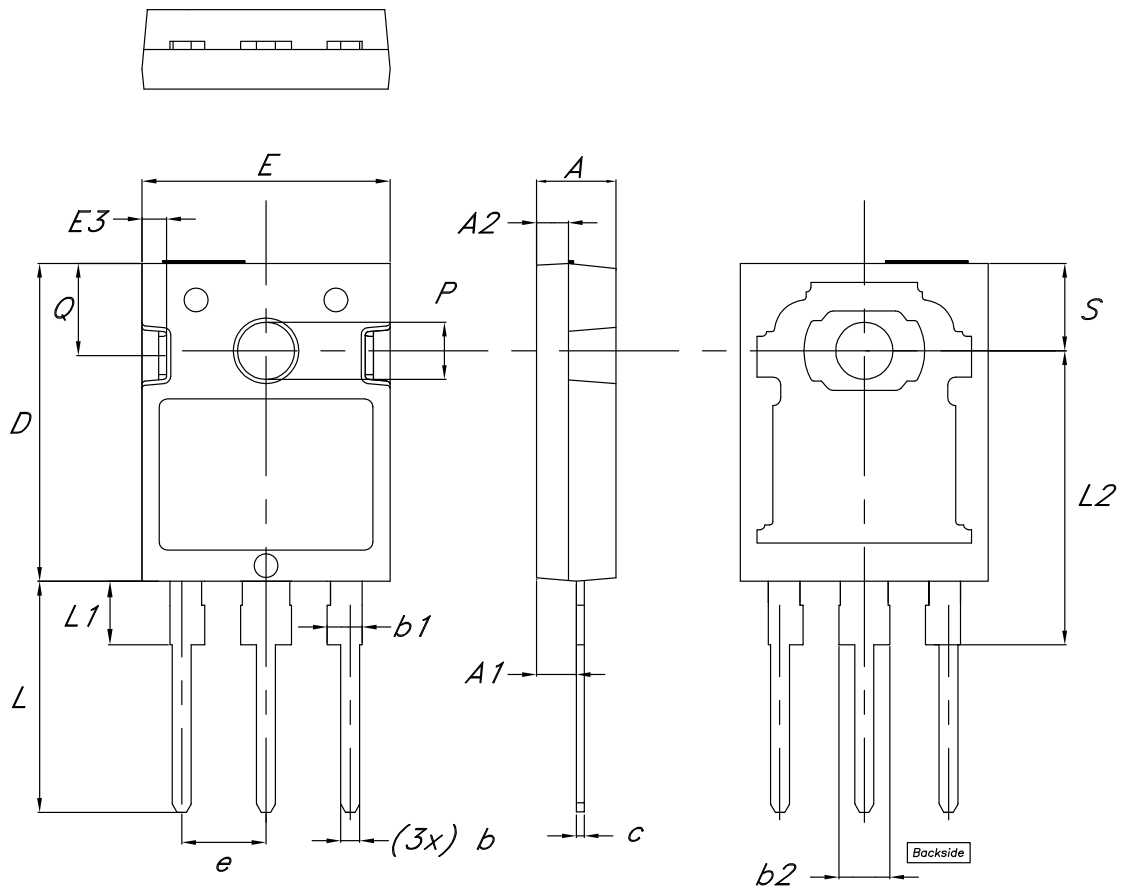
GIPD101020141502FSR

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 HiP247 package information

Figure 23. HiP247™ package outline



8581091_2

Table 8. HiP247™ package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.85	5.00	5.15
A1	2.20		2.60
A2	1.90	2.00	2.10
b	1.00		1.40
b1	2.00		2.40
b2	3.00		3.40
c	0.40		0.80
D	19.85	20.00	20.15
E	15.45	15.60	15.75
E3	1.45		1.65
e	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2	18.30	18.50	18.70
P	3.55		3.65
Q	5.65		5.95
S	5.30	5.50	5.70

Revision history

Table 9. Document revision history

Date	Revision	Changes
20-Mar-2018	1	First release
01-Mar-2019	2	Updated Table 3. On/off states . Updated package information.

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